

SN54ALS00A, SN54AS00, SN74ALS00A, SN74AS00 QUADRUPL 2-INPUT POSITIVE-NAND GATES

SDAS187A – APRIL 1982 – REVISED DECEMBER 1994

- Package Options Include Plastic Small-Outline (D) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

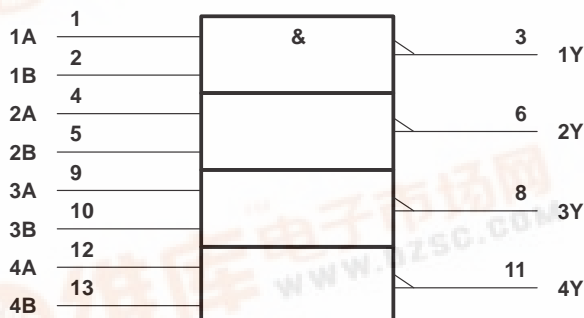
These devices contain four independent 2-input positive-NAND gates. They perform the Boolean functions $Y = \overline{A \bullet B}$ or $Y = \overline{A} + \overline{B}$ in positive logic.

The SN54ALS00A and SN54AS00 are characterized for operation over the full military temperature range of -55°C to 125°C . The SN74ALS00A and SN74AS00 are characterized for operation from 0°C to 70°C .

FUNCTION TABLE
(each gate)

INPUTS		OUTPUT
A	B	Y
H	H	L
L	X	H
X	L	H

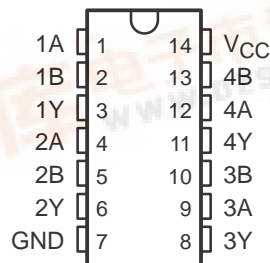
logic symbol†



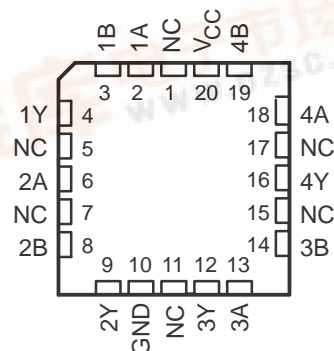
† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, J, and N packages.

SN54ALS00A, SN54AS00 . . . J PACKAGE
SN74ALS00A, SN74AS00 . . . D OR N PACKAGE
(TOP VIEW)



SN54ALS00A, SN54AS00 . . . FK PACKAGE
(TOP VIEW)

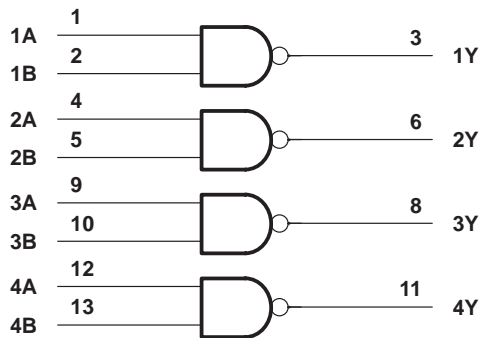


NC – No internal connection

SN54ALS00A, SN54AS00, SN74ALS00A, SN74AS00
QUADRUPLE 2-INPUT POSITIVE-NAND GATES

SDAS187A – APRIL 1982 – REVISED DECEMBER 1994

logic diagram (positive logic)



Pin numbers shown are for the D, J, and N packages.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage, V_{CC}	7 V
Input voltage, V_I	7 V
Operating free-air temperature range, T_A : SN54ALS00A	–55°C to 125°C
SN74ALS00A	0°C to 70°C
Storage temperature range	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN54ALS00A			SN74ALS00A			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.8 [‡]			0.8	V
				0.7 [§]				
I_{OH}	High-level output current			–0.4			–0.4	mA
I_{OL}	Low-level output current			4			8	mA
T_A	Operating free-air temperature	–55		125	0		70	°C

[‡] Applies over temperature range –55°C to 70°C

[§] Applies over temperature range 70°C to 125°C

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SDAS187A – APRIL 1982 – REVISED DECEMBER 1994

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		SN54ALS00A			SN74ALS00A			UNIT
			MIN	TYP†	MAX	MIN	TYP†	MAX	
V_{IK}	$V_{CC} = 4.5\text{ V}$, $I_I = -18\text{ mA}$				-1.2			-1.5	V
V_{OH}	$V_{CC} = 4.5\text{ V to } 5.5\text{ V}$, $I_{OH} = -0.4\text{ mA}$		$V_{CC} - 2$			$V_{CC} - 2$			V
V_{OL}	$V_{CC} = 4.5\text{ V}$	$I_{OL} = 4\text{ mA}$		0.25	0.4		0.25	0.4	V
		$I_{OL} = 8\text{ mA}$					0.35	0.5	
I_I	$V_{CC} = 5.5\text{ V}$, $V_I = 7\text{ V}$				0.1			0.1	mA
I_{IH}	$V_{CC} = 5.5\text{ V}$, $V_I = 2.7\text{ V}$				20			20	μA
I_{IL}	$V_{CC} = 5.5\text{ V}$, $V_I = 0.4\text{ V}$				-0.1			-0.1	mA
$I_{O\ddagger}$	$V_{CC} = 5.5\text{ V}$, $V_O = 2.25\text{ V}$		-20		-112	-30		-112	mA
I_{CCH}	$V_{CC} = 5.5\text{ V}$, $V_I = 0$			0.5	0.85		0.5	0.85	mA
I_{CCL}	$V_{CC} = 5.5\text{ V}$, $V_I = 4.5\text{ V}$			1.5	3		1.5	3	mA

† All typical values are at $V_{CC} = 5\text{ V}$, $T_A = 25^\circ\text{C}$.

‡ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, I_{OS} .

switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 4.5 V to 5.5 V, C _L = 50 pF, R _L = 500 Ω, T _A = MIN to MAX§				UNIT
			SN54ALS00A		SN74ALS00A		
			MIN	MAX	MIN	MAX	
t _{PLH}	A or B	Y	3	15	3	11	ns
t _{PHL}			2	9	2	8	

§ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

SN54ALS00A, SN54AS00, SN74ALS00A, SN74AS00

QUADRUPLE 2-INPUT POSITIVE-NAND GATES

SDAS187A – APRIL 1982 – REVISED DECEMBER 1994

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage, V_{CC}	7 V
Input voltage, V_I	7 V
Operating free-air temperature range, T_A : SN54AS00	–55°C to 125°C
SN74AS00	0°C to 70°C
Storage temperature range	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN54AS00			SN74AS00			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.8			0.8	V
I_{OH}	High-level output current			–2			–2	mA
I_{OL}	Low-level output current			20			20	mA
T_A	Operating free-air temperature	–55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	SN54AS00			SN74AS00			UNIT
		MIN	TYP [‡]	MAX	MIN	TYP [‡]	MAX	
V_{IK}	$V_{CC} = 4.5$ V, $I_I = -18$ mA			–1.2			–1.2	V
V_{OH}	$V_{CC} = 4.5$ V to 5.5 V, $I_{OH} = -2$ mA	$V_{CC} - 2$			$V_{CC} - 2$			V
V_{OL}	$V_{CC} = 4.5$ V, $I_{OL} = 20$ mA	0.35	0.5		0.35	0.5		V
I_I	$V_{CC} = 5.5$ V, $V_I = 7$ V		0.1			0.1		mA
I_{IH}	$V_{CC} = 5.5$ V, $V_I = 2.7$ V		20			20		μA
I_{IL}	$V_{CC} = 5.5$ V, $V_I = 0.4$ V		–0.5			–0.5		mA
I_{O}^{\S}	$V_{CC} = 5.5$ V, $V_O = 2.25$ V	–30		–112	–30		–112	mA
I_{CCH}	$V_{CC} = 5.5$ V, $V_I = 0$	2	3.2		2	3.2		mA
I_{CCL}	$V_{CC} = 5.5$ V, $V_I = 4.5$ V	10.8	17.4		10.8	17.4		mA

[‡] All typical values are at $V_{CC} = 5$ V, $T_A = 25^\circ\text{C}$.

^{\S} The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, I_{OS} .

switching characteristics (see Figure 1)

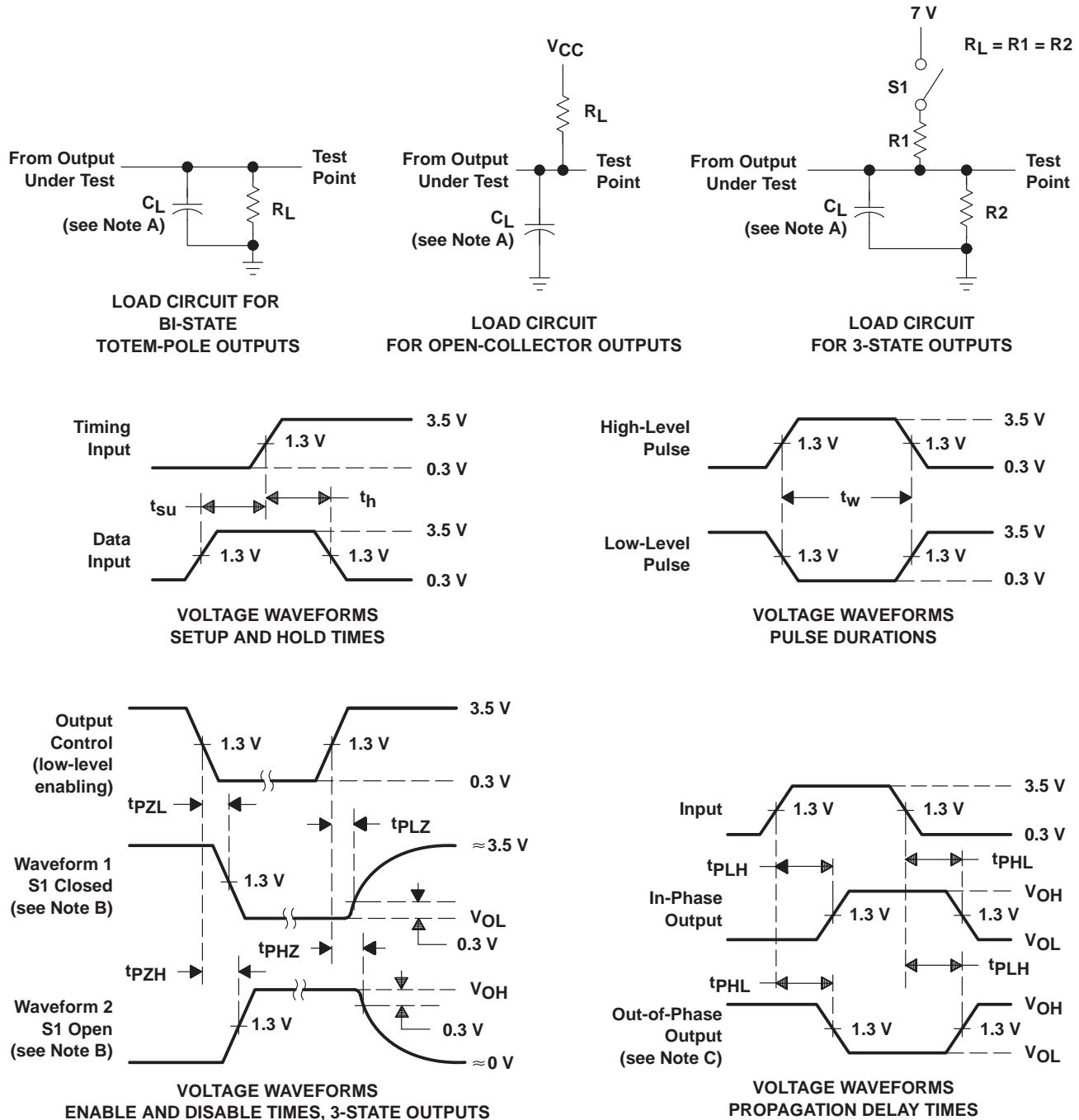
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 4.5 V to 5.5 V, C _L = 50 pF, R _L = 500 Ω, T _A = MIN to MAX††				UNIT
			SN54AS00		SN74AS00		
			MIN	MAX	MIN	MAX	
t _{PLH}	A or B	Y	1	5	1	4.5	ns
t _{PHL}			1	5	1	4	

^{\dagger\dagger} For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

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SDAS187A – APRIL 1982 – REVISED DECEMBER 1994

PARAMETER MEASUREMENT INFORMATION SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



- NOTES: A. C_L includes probe and jig capacitance.
 B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
 D. All input pulses have the following characteristics: $PRR \leq 1$ MHz, $t_r = t_f = 2$ ns, duty cycle = 50%.
 E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms

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